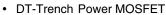


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# P-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $\Omega$ ) Max.	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)		
- 30	0.010 at V <sub>GS</sub> = - 10 V	- 50 <sup>d</sup>	43.1 nC		
- 30	0.015 at V <sub>GS</sub> = -4.5 V	- 50 <sup>d</sup>	43.1110		

#### **FEATURES**

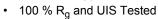




Low On-Resistance for Low Voltage Drop

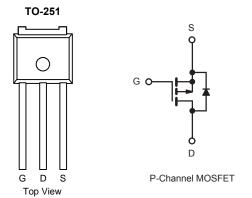
- Extended  $V_{GS}$  max. Rating: 25 V

COMPLIANT



#### **APPLICATIONS**

- · Battery, Load and Adaptor Switches
  - Notebook Computers
  - Notebook Battery Packs



Parameter	Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	- 30	V
Gate-Source Voltage		$V_{GS}$	± 25	
	T <sub>C</sub> = 25 °C		- 50 <sup>d</sup>	
Continuous Proin Current (T. = 150 °C)	T <sub>C</sub> = 70 °C		- 50 <sup>d</sup>	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	l <sub>D</sub>	- 23.1 <sup>a, b</sup>	
	T <sub>A</sub> = 70 °C		- 18.4 <sup>a, b</sup>	
Pulsed Drain Current (t = 100 µs)		I <sub>DM</sub>	- 300	A
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	1	- 50 <sup>d</sup>	
	T <sub>A</sub> = 25 °C	ls —	- 4.1 <sup>a, b</sup>	
Avalanche Current	L = 0.4 mH	I <sub>AS</sub>	- 25	
Single-Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	31.2	mJ
	T <sub>C</sub> = 25 °C		48	
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	В	31	w
	T <sub>A</sub> = 25 °C	P <sub>D</sub>	5 <sup>a, b</sup>	VV
	T <sub>A</sub> = 70 °C		3.2 <sup>a, b</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C
Soldering Recommendations (Peak Temperature)		260		

THERMAL RESISTANCE RATINGS						
Parameter	Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient <sup>a, c</sup>	t ≤ 10 s	R <sub>thJA</sub>	21	25	°C/W	
Maximum Junction-to-Case	Steady State	$R_{thJC}$	2.1	2.6	C/VV	

### Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under steady state conditions is 70  $^{\circ}\text{C/W}.$
- d. Package limited.

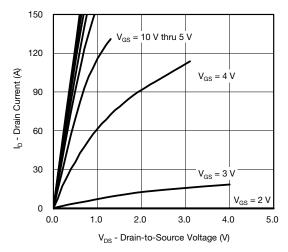


Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static						<u> </u>	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0$ , $I_D = -250 \mu A$	- 30			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		- 22		m\//°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = - 250 μA		4.1		mV/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1.2		- 2.5	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			± 100	nA	
		V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = 0 V			- 1		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 5	μΑ	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	V <sub>DS</sub> ≥ - 10 V, V <sub>GS</sub> = - 10 V	- 30			Α	
	_	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 15 A		0.010	0.011		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 10 A		0.015	0.017	Ω	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 10 V, I <sub>D</sub> = - 15 A		60		S	
Dynamic <sup>b</sup>	0.0						
Input Capacitance	C <sub>iss</sub>			5125		1	
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = 0 V, f = 1 MHz		615		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	23 4 7 63 4 7		554			
Treverse mansier capacitance	orss	V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 10 A		90	135	+	
Total Gate Charge	$Q_g$	VDS 10 V, VGS 10 V, ID 10 /V		43.1	65	nC	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 10 A		13.6	- 00		
Gate-Drain Charge	Q <sub>gd</sub>			28.8			
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.5	2.4	4.8	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>		0.0	15	30		
Rise Time	t <sub>r</sub>	V <sub>DD</sub> = - 15 V, R <sub>I</sub> = 1.5 Ω		12	24	-	
Turn-Off DelayTime	$t_{d(off)}$ $I_{D} \cong -10 \text{ A}, V_{GEN} = -10 \text{ V}, R_{g} = 1$			58	110		
Fall Time	t <sub>f</sub>	J J JEN J g		12	24		
Turn-On Delay Time	t <sub>d(on)</sub>			60	120	ns	
Rise Time	t <sub>r</sub>	V <sub>DD</sub> = - 15 V, R <sub>I</sub> = 1.5 Ω		60	120		
Turn-Off DelayTime	t <sub>d(off)</sub>	$I_D \simeq -10 \text{ A}, N_C = 1.3 \text{ s}_2$		52	100		
Fall Time	t <sub>f</sub>	S , GLIN - , y		26	52		
Drain-Source Body Diode Characterist	-				32		
Continous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			- 50		
Pulse Diode Forward Current (100 μs)	I <sub>SM</sub>	<u> </u>		1	- 300	Α	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = -3 A, V <sub>GS</sub> = 0		- 0.74	- 1.20	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			23	46	ns	
Body Diode Reverse Recovery Charge Q <sub>rr</sub>				12	24	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = -10 \text{ A, dI/dt} = 100 \text{ A/}\mu\text{s, T}_J = 25 °C$		9		ns	
Reverse Recovery Rise Time	t <sub>b</sub>			14		113	

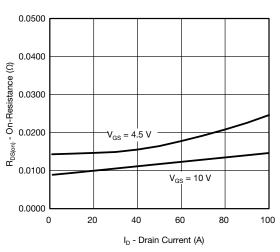
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

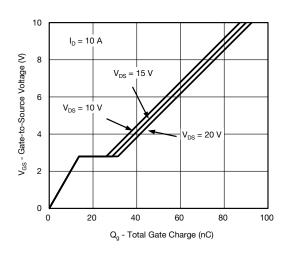




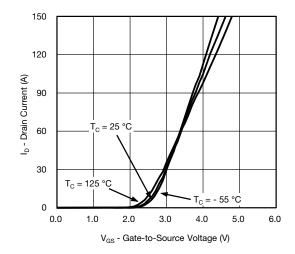
#### **Output Characteristics**



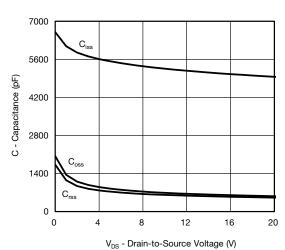
On-Resistance vs. Drain Current



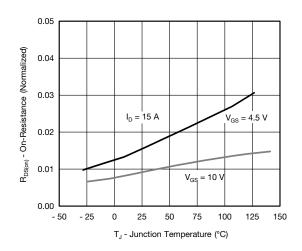
**Gate Charge** 



**Transfer Characteristics** 

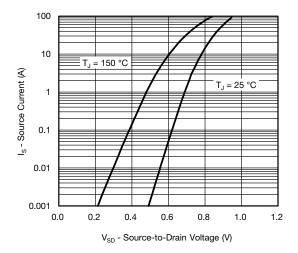


Capacitance

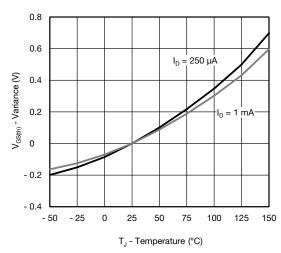


On-Resistance vs. Junction Temperature

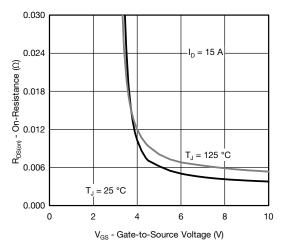




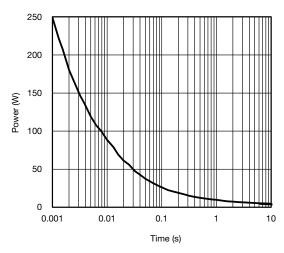
#### Source-Drain Diode Forward Voltage



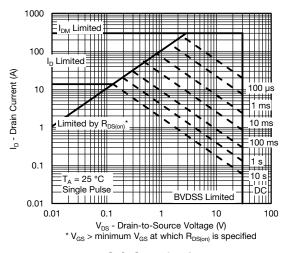
**Threshold Voltage** 



On-Resistance vs. Gate-to-Source Voltage

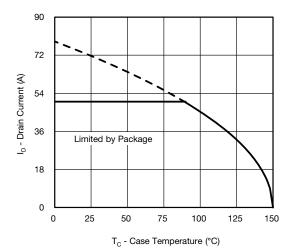


Single Pulse Power, Junction-to-Ambient

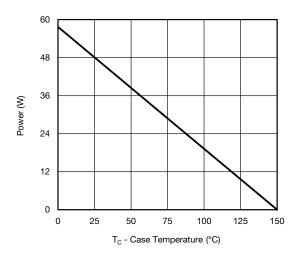


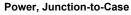
Safe Operating Area

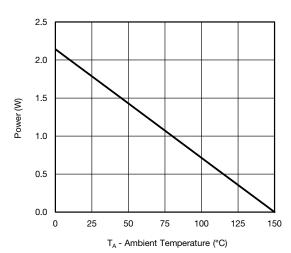




#### **Current Derating\***



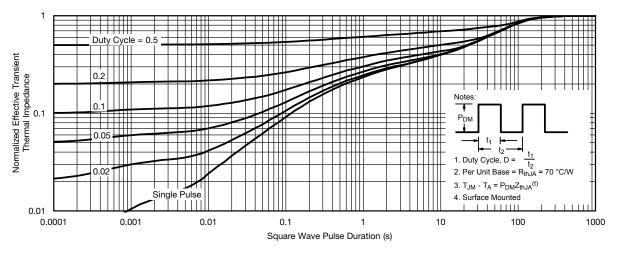




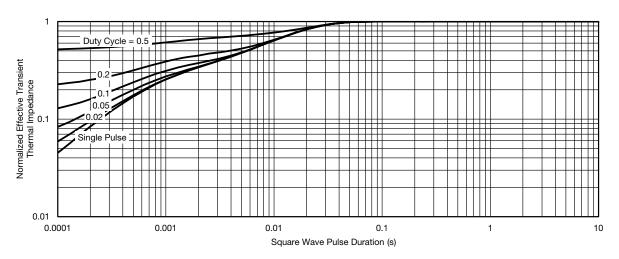
Power Derating, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





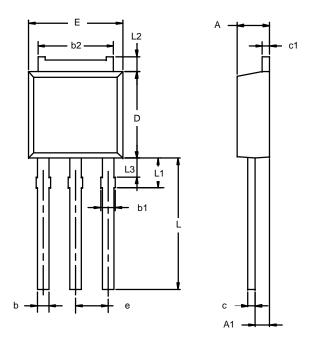
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



## TO-251AA (DPAK)



Note:	Dimension	L3 is for	reference only.
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	MILLIM	IETERS	INCHES		
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
<b>A</b> 1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
с1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
Е	6.48	6.73	0.255	0.265	
е	2.28	BSC	0.090 BSC		
L	8.89	9.53	0.350	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	
ECN: S-03946—Rev. E, 09-Jul-01 DWG: 5346					





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